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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/608,169	06/26/2003	Thomas J. McIntyre	BA-00577	8244
22590	7590	09/10/2008	EXAMINER	
BAE SYSTEMS			LAVARIAS, ARNEL C	
PO BOX 868			ART UNIT	
NASHUA, NH 03061-0868			PAPER NUMBER	
			2872	
			MAIL DATE	
			DELIVERY MODE	
			09/10/2008	
			PAPER	

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Office Action Summary

Application No.

10/608,169

Applicant(s)

MCINTYRE ET AL.

Examiner

Amel C. Lavarias

Art Unit

2872

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --
Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 30 June 2008.
- 2a) ☒ This action is **FINAL**. 2b) ☐ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-13 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1-13 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
- Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
- Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some * c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- 1) ☒ Notice of References Cited (PTO-892)
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) ☐ Information Disclosure Statement(s) (PTO/SI/02)
- 4) ☐ Interview Summary (PTO-413)
- 5) ☐ Notice of Informal Patent Application
- 6) ☐ Other: _____
- Paper No(s)/Mail Date _____

DETAILED ACTION

Response to Amendment

1. The amendments to the abstract of the disclosure in the submission dated 6/30/08 are acknowledged and accepted. In view of these amendments, the objections to the specification in Section 4 of the Office Action dated 3/28/08 are respectfully withdrawn.
2. The amendments to Claims 1-3, 7 in the submission dated 6/30/08 are acknowledged and accepted.
3. The cancellation of Claims 14-23 in the submission dated 6/30/08 is acknowledged and accepted. In view of these amendments, the rejections in Section 6 of the Office Action dated 3/28/08 are respectfully withdrawn.

Response to Arguments

4. The Applicants' arguments with respect to Claims 1-13 have been considered but are moot in view of the new ground(s) of rejection.
5. Claims 1-13 are now rejected as follows.

Claim Rejections - 35 USC § 103

6. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

7. This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).
8. Claims 1, 3-4, 6-8, 11 are rejected under 35 U.S.C. 103(a) as being unpatentable over Eggleton et al. (U.S. Patent No. 6438277), of record, in view of Rabiei et al. (P. Rabiei, W. H. Steier, C. Zhang, L. R. Dalton, 'Polymer micro-ring filters and modulators', J. Lightwave Tech., vol. 20, no. 11, November 2002, pp. 1968-1975.).

Regarding Claims 1, 3-4, 6-7, Eggleton et al. discloses a photonic circuit (Fig. 1) comprising a photonic resonator in the form of a thermally sensitive optical element 11 which may be a grating, a resonance ring or a solid body resonance cavity, which is part of a waveguide circuit 10, means for heating the photonic resonator in the form of heater 12, means for measuring a temperature of the photonic resonator 11 in the form of temperature-dependent resistive element (not shown), means for coupling the temperature sensor to the heater in the form of a feedback circuit 14 wherein the temperature detector measures the temperature of the photonic resonator and transmits signals to a current source, in order to increase or decrease the amount of heat provided to the heater, so that the temperature sensitive photonic resonator changes its wavelength response (line 64,

col. 2 to line 37, col. 3), thus allowing the photonic circuit to operate as a temperature-tunable wavelength switching control device. It is noted that in order for the system to associate a measured temperature with a desired temperature (which would cause the grating to transmit or reflect the desired wavelength), it is inherent that some kind of logic is used (e.g., in the simplest form whether a measured temperature is equal or not to a set temperature). Further, it is noted that the logic utilized includes a microprocessor controller which has memory and processor (See for example col. 3, lines 5-26).

Regarding Claims 8, 11, the change in the temperature is measured by measuring the resistance of wire 12, using a resistance detector 16, an ohmmeter, which in effect calculates the resistance by taking the values of a voltage and a current across the line (lines 5-11, col. 3).

Eggleton et al. discloses the invention as set forth above, but does not disclose the photonic circuit being capable of selecting a particular frequency of light in a deliberate stepped manner. However, Rabiei et al. teaches a polymer micro-ring resonator device (See for example Figures 2-4), wherein the resonator device is thermally tuned to adjust the center wavelength of the resonator device (See for example Abstract; Section III). Further, such resonator device may be temperature tuned to particular temperatures to achieve particular center wavelength output, i.e. the temperature may be stepped to produce a stepped output (See for example Figure 7). Thus, it would have been obvious to one having ordinary skill in the art at the time the invention was made to have the photonic circuit of Eggleton et al., be capable of selecting a particular frequency of light in a deliberate stepped manner, as taught by Rabiei et al., to allow the resonator device to

output particular, set wavelengths based on a particular application, such as in wavelength division multiplexing or demultiplexing of ITU standard wavelengths near 1550 nm.

9. Claim 2 is rejected under 35 U.S.C. 103(a) as being unpatentable over Eggleton et al. in view of Rabiei et al. as applied to Claims 1, 3-4, 6-8, 11 above, and further in view of Heimala et al. (P. Heimala, P. Katila, J. Aarnio, 'Integrated optical ring resonator on silicon with thermal tuning and in situ temperature measurement', Proc. SPIE, vol. 2695, January 1996, pp. 71-77.).

Eggleton et al. in view of Rabiei et al. discloses the invention as set forth above in Claims 1, 3-4, 6-8, 11, except for the photonic resonator, heating means, temperature measuring means, and coupling means being etched onto an integrated circuit chip. However, Heimala et al. teaches an integrated optical ring resonator device with associated thermal tuning structure (See for example Abstract; Figures 1, 3) on a silicon substrate. Thus, it would have been obvious to one having ordinary skill in the art at the time the invention was made to have the photonic resonator, heating means, temperature measuring means, and coupling means be etched onto an integrated circuit chip, as taught by Rabiei et al., in the photonic circuit of Eggleton et al. in view of Rabiei et al., to allow for *in situ* measurement and thermal control of the resonator device by taking advantage of the close proximity of the thermal sensor and heater to the resonator ring device.

10. Claims 5, 9-10 are rejected under 35 U.S.C. 103(a) as being unpatentable over Eggleton et al. in view of Rabiei et al. as applied to Claims 1, 3-4, 6-8, 11 above, and further in view of Koizumi et al. (U.S. Patent No. 5696543), of record.

Eggleton et al. in view of Rabiei et al. discloses all the limitations of the above claims except for specifying that the metal wire of the temperature sensor is aluminum.

Koizumi et al. discloses a temperature sensor device wherein an aluminum wire is used as temperature sensor element 6 (Fig. 1, lines 44-56, col. 3). It would have been obvious to one of ordinary skill in the art at the time the invention was made to use an aluminum wire as a simple temperature sensor, as taught by Koizumi et al., since aluminum has very good thermal properties in terms of its thermal coefficient.

11. Claim 12 is rejected under 35 U.S.C. 103(a) as being unpatentable over Eggleton et al. in view of Rabiei et al. as applied to Claims 1, 3-4, 6-8, 11 above, and further in view of Schwindt et al. (U.S. Patent No. 6720782), of record.

Eggleton et al. in view of Rabiei et al. discloses all the limitations of the above claim except for specifying that during the measurement of the resistance of the wire, the value of voltage is taken by using a voltmeter connected to the wire via a Kelvin connection. Schwindt et al. discloses a measurement probe used in conjunction with low-current and low-voltage measurements of wafers and other electronic test devices, wherein Schwindt et al. teaches that a voltmeter may be connected to an interconnection point which comprises a Kelvin connection (lines 26-65, col. 1). It would have been obvious to one of ordinary skill in the art at the time the invention was made to connect the voltmeter to the wire via a Kelvin connection in the device of Eggleton et al. in view of Rabiei et al., as taught by Schwindt et al., since Kelvin connections compensate for voltage losses caused by line resistances which would otherwise cause errors in low-voltage measurements (lines 52-54, col. 1 in Schwindt et al.).

12. Claim 13 rejected under 35 U.S.C. 103(a) as being unpatentable over Eggleton et al. in view of Rabiei et al. as applied to Claims 1, 3-4, 6-8, 11 above, and further in view of Sorin et al. (U.S. Patent No. 5982791), of record.

Eggleton et al. in view of Rabiei et al. discloses the invention as set forth above in Claim 7, except for the measure of temperature being used as a key into a lookup table, said lookup table comprising different frequencies selected by said resonator at different temperatures. However, the use of lookup tables to correlate one parameter to another is well known and conventional in the art. For example, Sorin et al. teaches a conventional optical system utilizing a series of fiber Bragg gratings for WDM applications (See for example Abstract; Figures 3, 6-12). In addition, Sorin et al. teaches that the operating wavelength of the fiber Bragg gratings may be adjusted by a controller (See for example 104 in Figure 7) by use of a lookup table that includes wavelength vs. temperature information for the Bragg grating (See col. 8, line 44-col. 9, line 22). Thus, it would have been obvious to one having ordinary skill in the art at the time the invention was made to have the measure of temperature be used as a key into a lookup table, said lookup table comprising different frequencies selected by said resonator at different temperatures, as taught by Sorin et al., in the process of Eggleton et al. in view of Rabiei et al., for the purpose of providing fast, dynamic feedback and tuning of the fiber Bragg grating.

Conclusion

13. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP

§ 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

14. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Arnel C. Lavarias whose telephone number is 571-272-2315. The examiner can normally be reached on M-F 10:00 AM - 6:30 PM EST.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Stephone B. Allen can be reached on 571-272-2434. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

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9/4/08

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